

ET3DV6 SN:1788

September 30, 2004

Probe ET3DV6

SN:1788

Manufactured:

May 28, 2003

Last calibrated:

August 29, 2003

Recalibrated:

September 30, 2004

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

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DASY - Parameters of Probe: ET3DV6 SN:1788

Sensitivity in Free Space ^A	
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Diode Compression^B

NormX	1.68 ± 9.9%	$\mu V/(V/m)^2$	DCP X	94 mV
NormY	1.70 ± 9.9%	$\mu V/(V/m)^2$	DCP Y	94 mV
NormZ	1.74 ± 9.9%	$\mu V/(V/m)^2$	DCP Z	94 mV

Sensitivity in Tissue Simulating Liquid (Conversion Factors)

Please see Page 8.

Boundary Effect

TSL

900 MHz Typical SAI

Typical SAR gradient: 5 % per mm

Sensor Center to Phantom Surface Distance		3.7 mm	4.7 mm
SAR _{be} [%]	Without Correction Algorithm	8.1	4.4
SAR _{be} [%]	With Correction Algorithm	0.7	0.1

TSL

1810 MHz

Typical SAR gradient: 10 % per mm

Sensor Center to Phantom Surface Distance		3.7 mm	4.7 mm
SAR _{be} [%]	Without Correction Algorithm	12.0	8.2
SAR _{be} [%]	With Correction Algorithm	0.9	0.1

Sensor Offset

Probe Tip to Sensor Center

2.7 mm

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL (see Page 8).

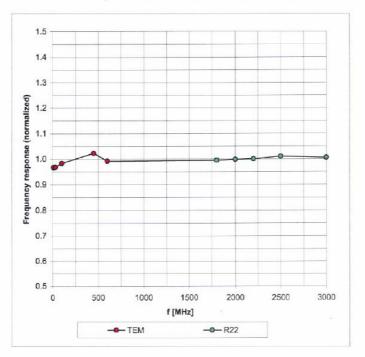
⁸ Numerical linearization parameter: uncertainty not required.

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Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)



Uncertainty of Frequency Response of E-field: ± 6.3% (k=2)

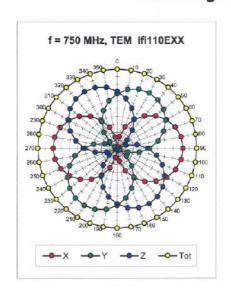
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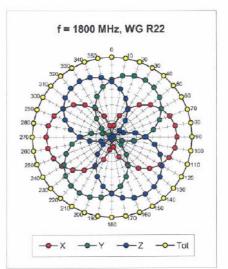


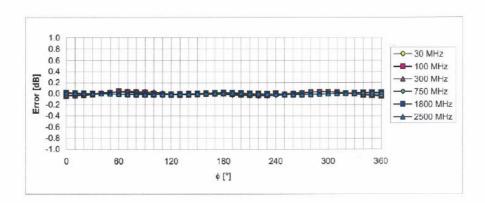
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Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$







Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

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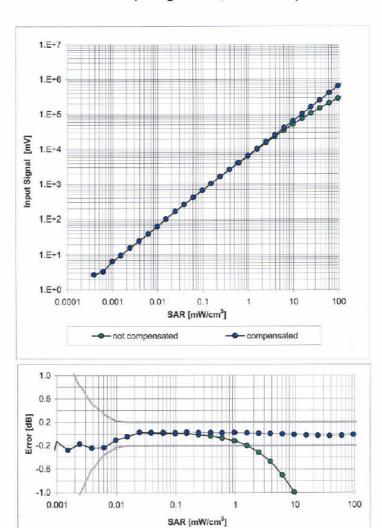
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Dynamic Range f(SAR_{head})

(Waveguide R22, f = 1800 MHz)



Uncertainty of Linearity Assessment: ± 0.6% (k=2)

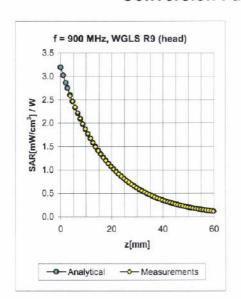
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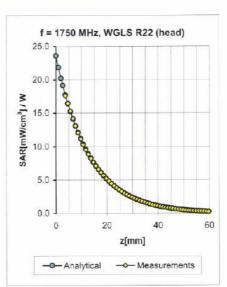
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Conversion Factor Assessment





f [MHz]	Validity [MHz] ^C	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
835	± 50 / ± 100	Head	41.5 ± 5%	0.90 ± 5%	1.12	1.42	6.74 ± 11.0% (k=2)
900	$\pm 50 / \pm 100$	Head	$41.5\pm5\%$	0.97 ± 5%	1.07	1.44	6.63 ± 11.0% (k=2)
1750	$\pm 50 / \pm 100$	Head	$40.0 \pm 5\%$	1.40 ± 5%	0.56	2.31	5.37 ± 11.0% (k=2)
1900	± 50 / ± 100	Head	$40.0\pm5\%$	1.40 ± 5%	0.55	2.42	5.16 ± 11.0% (k=2)
2000	± 50 / ± 100	Head	$40.0 \pm 5\%$	1.40 ± 5%	0.54	2.59	4.88 ± 11.0% (k=2)
2450	\pm 50 / \pm 100	Head	$39.2\pm5\%$	1.80 ± 5%	0.65	2.22	4.56 ± 11.8% (k=2)
835	± 50 / ± 100	Body	55.2 ± 5%	0.97 ± 5%	1.04	1.52	6.53 ± 11.0% (k=2)
900	± 50 / ± 100	Body	55.0 ± 5%	1.05 ± 5%	0.99	1.56	6.17 ± 11.0% (k=2)
1750	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.53	2.74	4.73 ± 11.0% (k=2)
1900	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.55	2.82	4.56 ± 11.0% (k=2)
2000	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.54	2.98	4.43 ± 11.0% (k=2)
2450	± 50 / ± 100	Body	52.7 ± 5%	1.95 ± 5%	0.72	2.00	4.26 ± 11.8% (k=2)

 $^{^{\}rm C}$ The validity of \pm 100 MHz only applies for DASY 4.3 B17 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

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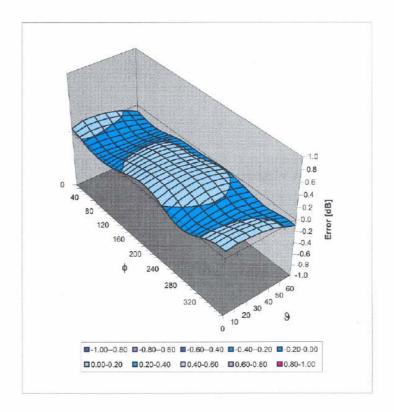
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Deviation from Isotropy in HSL

Error (4, 3), f = 900 MHz



Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

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Client

Sporton (Auden)

Accreditation No.: SCS 108

Certificate No: DAE3-577_Nov04

Object	DAE3 - SD 000 D03 AA - SN: 577						
Calibration procedure(s)	QA CAL-06.v10 Calibration proces	dure for the data acquisition unit (DAE)				
Calibration date:	on date: November 17, 2004						
Condition of the calibrated item	In Tolerance						
Calibration Equipment used (M&Tt	E critical for calibration)						
Primary Standards	ID#	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration				
		Cal Date (Calibrated by, Certificate No.) 7-Sep-04 (Sintrel, No.E-040073)	Scheduled Calibration Sep-05				
Fluke Process Calibrator Type 702							
Fluke Process Calibrator Type 702 Secondary Standards	SN: 6295803	7-Sep-04 (Sintrel, No.E-040073)	Sep-05				
Fluke Process Calibrator Type 702 Secondary Standards	SN: 6295803	7-Sep-04 (Sintrel, No.E-040073) Check Date (in house)	Sep-05 Scheduled Check				
Fluke Process Calibrator Type 702 Secondary Standards	SN: 6295803	7-Sep-04 (Sintrel, No.E-040073) Check Date (in house)	Sep-05 Scheduled Check				
Fluke Process Calibrator Type 702 Secondary Standards	SN: 6295803	7-Sep-04 (Sintrel, No.E-040073) Check Date (in house)	Sep-05 Scheduled Check				
Fluke Process Calibrator Type 702 Secondary Standards	SN: 6295803 ID # SE UMS 006 AB 1002	7-Sep-04 (Sintrel, No.E-040073) Check Date (in house) 16-Jul-04 (SPEAG, in house check)	Sep-05 Scheduled Check In house check Jul-05				
Fluke Process Calibrator Type 702 Secondary Standards Calibrator Box V1.1	SN: 6295803	7-Sep-04 (Sintrel, No.E-040073) Check Date (in house)	Sep-05 Scheduled Check				
Fluke Process Calibrator Type 702 Secondary Standards Calibrator Box V1.1	SN: 6295803 ID # SE UMS 006 AB 1002 Name	7-Sep-04 (Sintrel, No.E-040073) Check Date (in house) 16-Jul-04 (SPEAG, in house check) Function	Sep-05 Scheduled Check In house check Jul-05				
Primary Standards Fluke Process Calibrator Type 702 Secondary Standards Calibrator Box V1.1 Calibrated by:	SN: 6295803 ID # SE UMS 006 AB 1002 Name	7-Sep-04 (Sintrel, No.E-040073) Check Date (in house) 16-Jul-04 (SPEAG, in house check) Function	Sep-05 Scheduled Check In house check Jul-05				

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Accreditation No.: SCS 108

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Glossary

DAE digital acquisition electronics

Connector angle information used in DASY system to align probe sensor X to the robot

coordinate system.

Methods Applied and Interpretation of Parameters

- DC Voltage Measurement: Calibration Factor assessed for use in DASY system by comparison with a calibrated instrument traceable to national standards. The figure given corresponds to the full scale range of the voltmeter in the respective range.
- Connector angle: The angle of the connector is assessed measuring the angle mechanically by a tool inserted. Uncertainty is not required.
- The following parameters contain technical information as a result from the performance test and require no uncertainty.
- DC Voltage Measurement Linearity: Verification of the Linearity at +10% and -10% of the nominal calibration voltage. Influence of offset voltage is included in this measurement.
- Common mode sensitivity: Influence of a positive or negative common mode voltage on the differential measurement.
- Channel separation: Influence of a voltage on the neighbor channels not subject to an input voltage.
- AD Converter Values with inputs shorted: Values on the internal AD converter corresponding to zero input voltage
- Input Offset Measurement: Output voltage and statistical results over a large number of zero voltage measurements.
- Input Offset Current: Typical value for information; Maximum channel input offset current, not considering the input resistance.
- Input resistance: DAE input resistance at the connector, during internal auto-zeroing and during measurement.
- Low Battery Alarm Voltage: Typical value for information. Below this voltage, a battery alarm signal is generated.
- Power consumption: Typical value for information. Supply currents in various operating modes.

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DC Voltage Measurement

A/D - Converter Resolution nominal

 $\begin{array}{lll} \mbox{High Range:} & \mbox{1LSB} = & \mbox{6.1}\mu\mbox{V} \,, & \mbox{full range} = & \mbox{-100...+300 mV} \\ \mbox{Low Range:} & \mbox{1LSB} = & \mbox{61nV} \,, & \mbox{full range} = & \mbox{-1......+3mV} \end{array}$

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Calibration Factors	х	Y	Z
High Range	404.437 ± 0.1% (k=2)	403.891 ± 0.1% (k=2)	404.359 ± 0.1% (k=2)
Low Range	3.94121 ± 0.7% (k=2)	3.89867 ± 0.7% (k=2)	3.95408 ± 0.7% (k=2)

Connector Angle

127 ° ± 1 °

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Appendix

1. DC Voltage Linearity

Input (μV)	Reading (μV)	Error (%)
200000	200000.6	0.00
20000	20001.77	0.01
20000	-19991.81	-0.04
200000	199999.7	0.00
20000	19999.20	0.00
20000	-19994.82	-0.03
200000	200000.2	0.00
20000	19996.22	-0.02
20000	-19996.74	-0.02
	200000 20000 20000 20000 20000 20000 20000 20000	200000 200000.6 20000 20001.77 20000 -19991.81 20000 199999.7 20000 19999.20 20000 -19994.82 20000 20000.2 20000 19996.22

Low Range		Input (μV)	Reading (μV)	Error (%)
Channel X	+ Input	2000	2000	0.00
Channel X	+ Input	200	200.05	0.03
Channel X	- Input	200	-200.88	0.44
Channel Y	+ Input	2000	1999.9	0.00
Channel Y	+ Input	200	199.73	-0.13
Channel Y	- Input	200	-200.53	0.27
Channel Z	+ Input	2000	2000.1	0.00
Channel Z	+ Input	200	199.25	-0.38
Channel Z	- Input	200	-201.42	0.71

2. Common mode sensitivity

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Common mode Input Voltage (mV)	High Range Average Reading (μV)	Low Range Average Reading (μV)
Channel X	200	13.15	12.30
	- 200	-12.61	-12.86
Channel Y	200	-7.43	-7.53
	- 200	6.30	6.52
Channel Z	200	-0.16	0.31
	- 200	-1.51	-1.48

3. Channel separation

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Input Voltage (mV)	Channel X (μV)	Channel Y (μV)	Channel Z (μV)
Channel X	200	-	1.90	-0.22
Channel Y	200	1.47	-	4.60
Channel Z	200	-1.40	-0.08	

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4. AD-Converter Values with inputs shorted

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	High Range (LSB)	Low Range (LSB)
Channel X	15948	15814
Channel Y	15960	16073
Channel Z	16236	16172

5. Input Offset Measurement

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Input 10MΩ

	Average (μV)	min. Offset (μV)	max. Offset (μV)	Std. Deviation (µV)
Channel X	0.03	-3.07	1.24	0.58
Channel Y	-0.66	-2.19	1.96	0.55
Channel Z	-0.91	-2.82	0.42	0.39

6. Input Offset Current

Nominal Input circuitry offset current on all channels: <25fA

7. Input Resistance

	Zeroing (MOhm)	Measuring (MOhm)
Channel X	0.2000	199.3
Channel Y	0.2000	200.4
Channel Z	0.2001	199.5

8. Low Battery Alarm Voltage (verified during pre test)

Typical values	Alarm Level (VDC)
Supply (+ Vcc)	+7.9
Supply (- Vcc)	-7.6

9. Power Consumption (verified during pre test)

Typical values	Switched off (mA)	Stand by (mA)	Transmitting (mA)
Supply (+ Vcc)	+0.0	+6	+14
Supply (- Vcc)	-0.01	-8	-9

10. Common Mode Bit Generation (verified during pre test)

Typical values	Bit set to High at Common Mode Error (VDC)	
Channel X, Y, Z	+1.25	

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